

Notice of References Cited

Application/Control No.

10/536,492

Applicant(s)/Patent Under
Reexamination
KIM ET AL.

Examiner

Zachary C. Tucker

Art Unit

1624

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Kugucheva et al, "Gas-Chromatographic Analysis of Trace Impurities for Ethylbenzene, o-, m- and p-xylenes in Toluene" Neftepererabotka i Neftekhimiya, vol. 3, pages 35-36 (1983) RUSSIAN-LANGUAGE VERSION AND ENGLISH TRANSLATION.
	V	Iida and Okada "Determination of Trace Impurities in Toluene by Gas Chromatography-Chemical Ionization Mass Spectrometry" Bunseki Kagaku, vol. 26(9), pages 630-634 (1977) JAPANESE-LANGUAGE VERSION AND ENGLISH TRANSLATION.
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.